

FWS-7200

Environment Test Report

Report NO: 12I020026

Summary	<p><input checked="" type="checkbox"/> Pass</p> <p><input type="checkbox"/> Fail</p> <p>Note : There is/are ____ defect(s) not list in the report, please check it in the DTS Website.</p> <p><input type="checkbox"/> Pass with Deviation</p> <p>Comment : _____</p>
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Issue date

2012-09-12

Approval

Tom Lin

Test Engineer

Clement Chien

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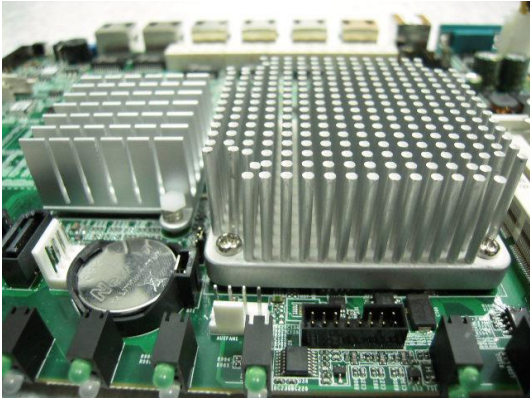
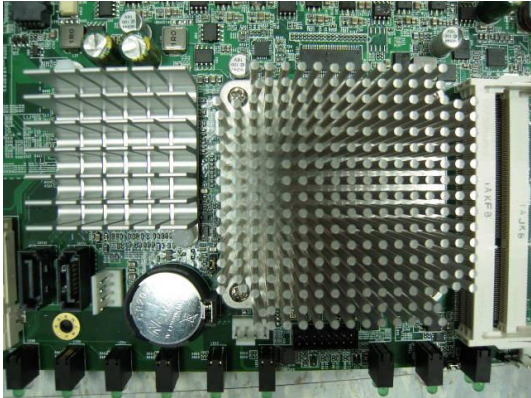
Testing Result

Num	Test item list	Result	Remark
1	Temperature rise test	Pass	
2	Temperature cycle operation test	Pass	
3	High temperature storage test	Pass	
4	Low temperature storage test	Pass	
5	Humidity test	Pass	
6	Cold start and hot start test	Pass	

Configuration of EUT

Num	Item	Spec
1.	System:	FWS-7200 A1.0
	1.Main board	FWS-7200 A1.0 (Bios Ver. R0.0)
	2.CPU Type	Intel Atom D525 / 1.8GHz
	2. Chipset	Intel ICH8M
	3. Memory	DSL DDR3 1066 4GB CL7
	4. SATA HDD	TOSHIBA 2.5" MK1676GSX 160GB x2
	5. Test Software	Windows 7 / Run BurnIn test 7.0
2.	Adapter :	FSP180-50LE

Heat Sink



Temperature rise test

Test Date: 06-18-2012

Test Product: FWS-7200

Test Site: AAEMON QE Internal Lab.

Test Standard: Refer to EN 61131-2(94), UL508 (94)

Temperature Measurement:

40 Channel Thermal Recorder:

YOKOGAWA Inc,

Model: DA100

Date of Calibration: 10/12/2011

Serial Number: 12A323190

Test Condition:

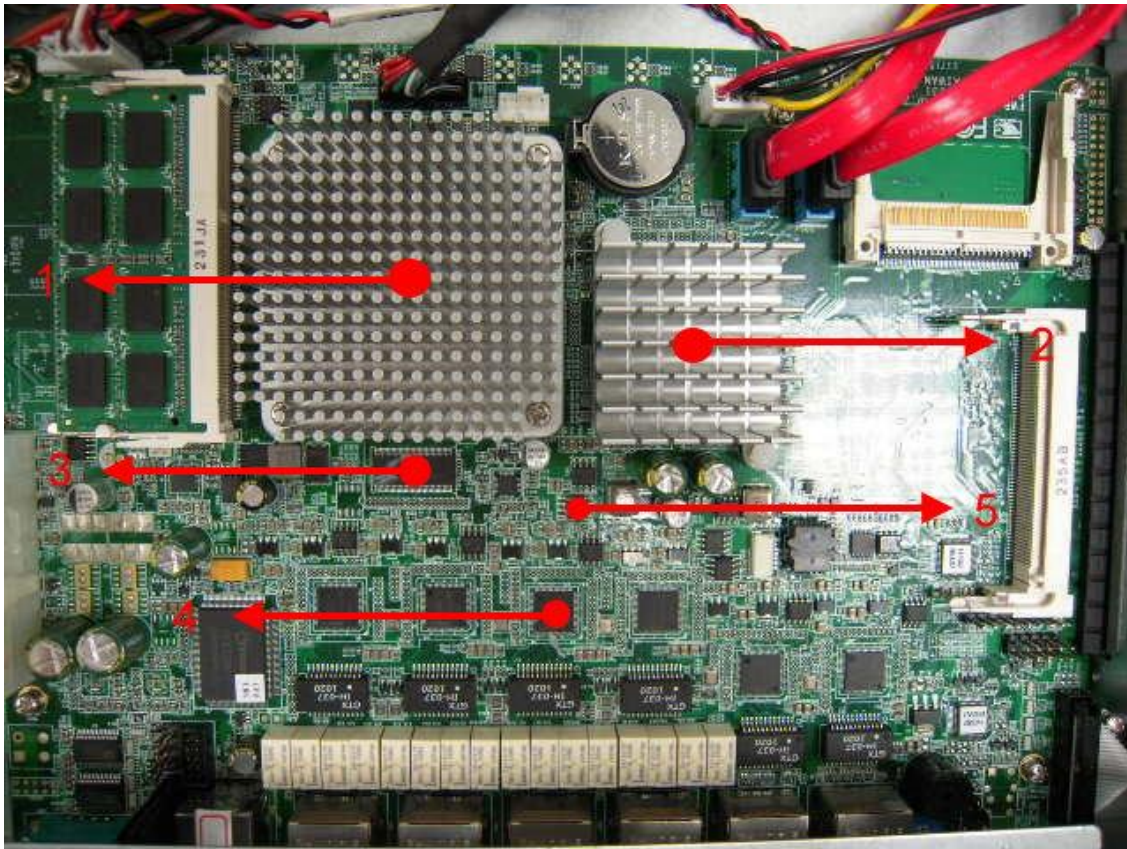
Ambient temperature:40°C

Continuous running till thermal stability (within less than 1°C)

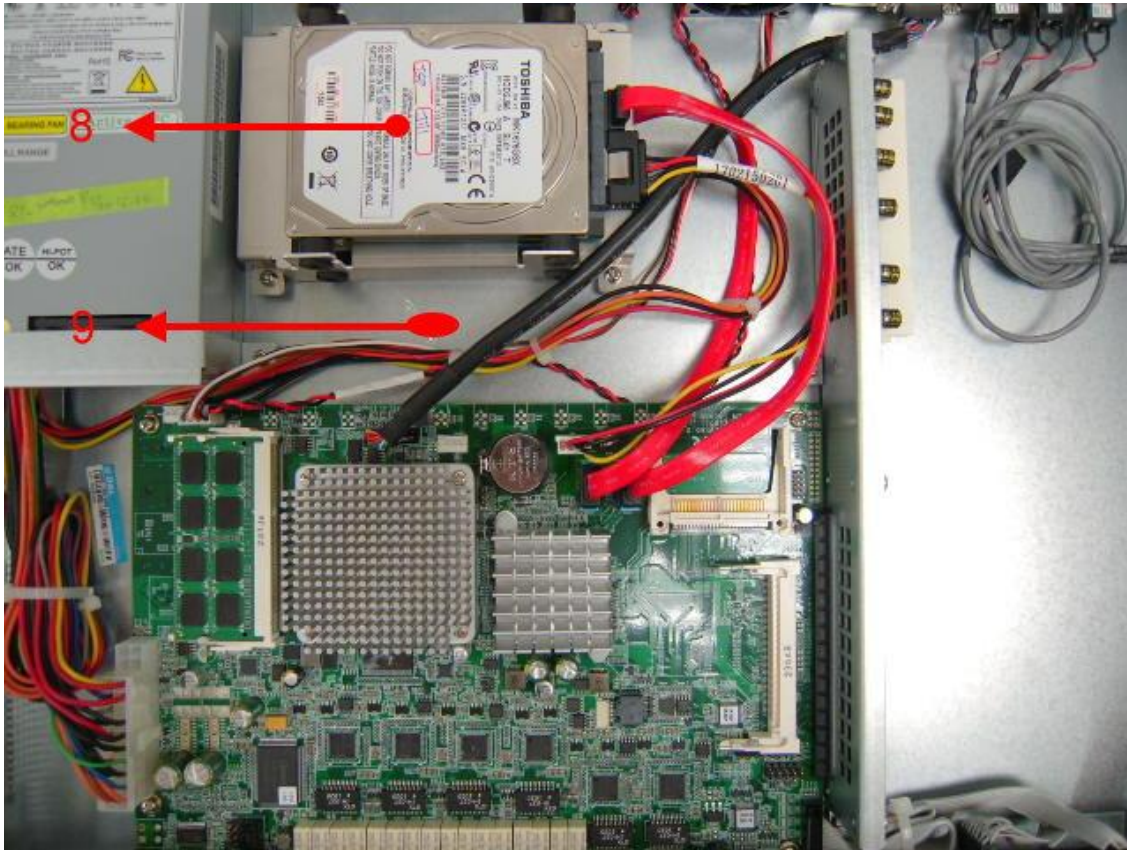
Test Software:

Windows 7 / Run PassMark Burn In Test 7.0

Terminal Recorder:



Temperature rise test



Temperature rise test

Thermal profile data:

Point	Temp. Stage(°C)	Spec	40	Note
01.U33 - (TF)Intel.CPU.D.DUAL.CORE.D525.1.80GHz		100	84.2	
02.U32- (TF)Chipset ICH8M.INTEL.DW82801HBM SLJ4Y		115	60.2	
03.U29- (TF) CLOCK GENERATOR.IDT.9LPRS501PGLF		115	84.1	
04.U21- (TF)PCI-E GigaBit Ethernet Chipset.Intel.WG82574L SLBA8		109	84.4	
05.U19- (TF)8P.8K SPI Bus Serial EEPROM.ATMEL.AT25080B-SSHL-T		125	75.4	
06. Memory		85	69.4	
07. HDD(Down side)		85	57.3	
08. HDD(Top side)		85	54.7	
09. Control Box Inside Air Temperature		N/A	53.1	
15. Control Box Surface Temperature		N/A	41.9	
11. Chamber Air Temperature		N/A	39.9	

Note(*):

1. "Tc" indicates the component's case maximum temperature value specified in its datasheet.
2. "Tm" indicates the measured Tc value under working environmental temperature within product specification.

3. Judgment Criteria:

- **Fail** : $T_m > T_c$; The measured value is over specification.
- **Margin Pass** : $T_c > T_m > T_c - 5^\circ\text{C}$; The measured value is within specification with margin.
It is strongly recommended to add thermal dissipation design for better reliability.
- **Pass** : $T_m < T_c - 5^\circ\text{C}$; The measured value is with safety margin.

Sample Configuration & Quantity Under Test:

Quantity: 1 (FWS-7200)

Test Result:

No issues were found during the temperature rise operation test.

Temperature cycle test

Test Date: 06-05 ~ 07-2012

Test Product: FWS-7200

Test Site: AAEON QE Internal Lab.

Test Standard: Refer to IEC68-2-14 Testing procedures
Test N: Change of temperature Test

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.

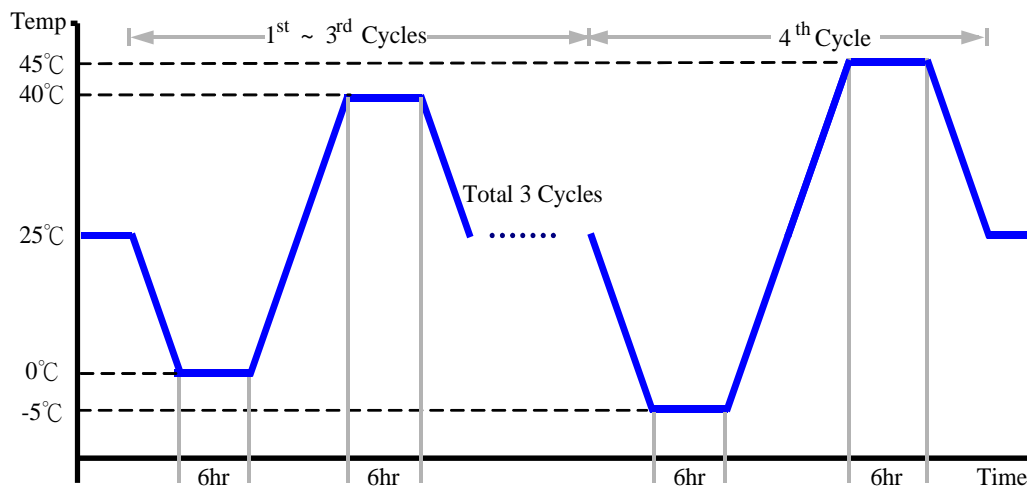
Model: THS-D75-100+LN2

Date of Calibration: 10/13/11

Serial Number: 6487KT

Test Condition:

1. Test Low Temperature: 0°C (1~3 cycles)
-5°C (4th cycle)
2. Test High Temperature: 40°C (1~3 cycles)
45°C (4th cycle)
3. Test dwell time: 6Hrs
4. Temperature slope: 2°C/min
5. Test cycle: 4 cycles
6. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (FWS-7200)

Test Result:

No issues were found during the temperature operation cycle test.

High temperature storage test

Test Date: 05-28 ~ 29-2012

Test Product: FWS-7200

Test Site: AAEON QE Internal Lab.

Test Standard: Refer to IEC 68-2-2 Testing procedures
Test Bb: Dry Heat Test (Non-operation)

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.

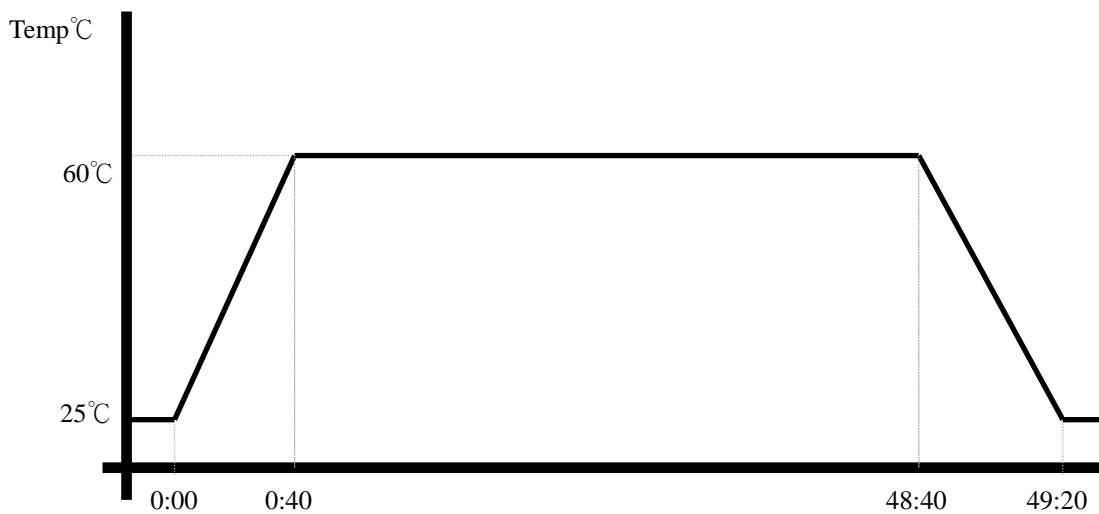
Model: THS-D75-100+LN2

Date of Calibration: 10/13/11

Serial Number: 6487KT

Testing Item:

1. Test Temperature: 60°C
2. Test Times: 48Hrs
3. Test Software: Windows 7 / Run PassMark Burn In Test 7.0
4. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (FWS-7200)

Test Result:

No issues were found after the high temperature storage test.

Low temperature storage test

Test Date: 05-30 ~ 31-2012

Test Product: FWS-7200

Test Site: AAEON QE Internal Lab.

Test Standard: Refer to IEC 68-2-1 Testing procedures
Test Ab: Cold Test (Non-operation)

Test Equipment:

Programmable Temperature & Humidity Chamber

K.SON. INS. TECH. CORP.

Model: THS-D75-100+LN2

Date of Calibration: 10/13/11

Serial Number: 6487KT

Testing Item:

1. Test Temperature: -20°C
2. Test Times: 48Hrs
3. Test Software: Windows 7 / Run PassMark Burn In Test 7.0
4. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (FWS-7200)

Test Result:

No issues were found after the low temperature storage test.

Humidity test

Test Date: 06-01 ~ 02-2012

Test Product: FWS-7200

Test Site: AAEON QE Internal Lab.

Test Standard: Refer to IEC 68-2-3 Testing procedures
Test Ca: Damp heat, steady state (Non-operation)

Test Equipment:

Programmable Temperature & Humidity Chamber

K.SON. INS. TECH. CORP.

Model: THS-D75-100+LN2

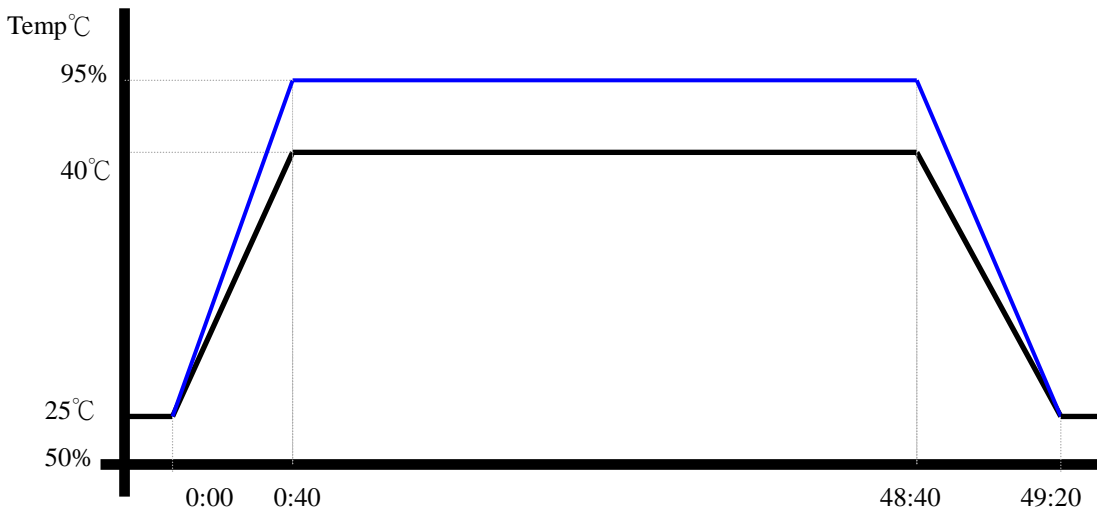
Date of Calibration: 10/13/11

Serial Number: 6487KT

Testing Item:

1. Test Temperature: 40°C
2. Test Humidity: 95%RH
3. Test Times: 48Hrs
4. Test Software: Windows 7 / Run PassMark Burn In Test 7.0
5. Test Environment Curve:

Humidity %



Sample Configuration & Quantity Under Test:

Quantity: 1 (FWS-7200)

Test Result:

No issues were found after the humidity storage test.

Cold start and hot start test

Test Date: 06-03 ~ 04-2012

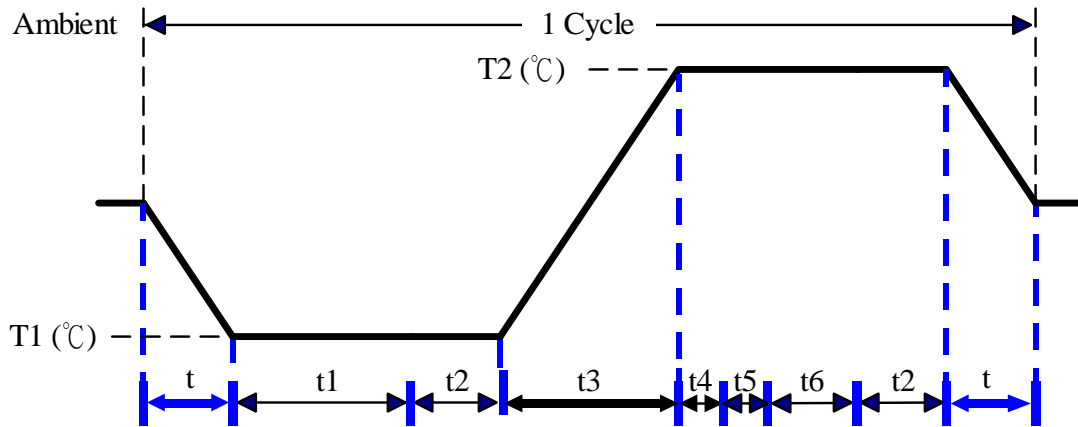
Test Product: FWS-7200

Test Site: AAEON QE Internal Lab.

Test Standard: Refer to IEC 68-2-14 Testing procedures
Test N: Change of temperature Test

Test Equipment:
 Programmable Temperature & Humidity Chamber
 K.SON. INS. TECH. CORP.
 Model: THS-D75-100+LN2
 Date of Calibration: 10/13/11
 Serial Number: 6487KT

Test Condition:



Parameters	Description
T1	-5°C
T2	45°C
t1	4 hrs
t2, t6	2 hrs
t4, t5	1hrs
t, t3	2°C/min
n (Cycle)	1

t = temperature slope
 t , t1, t6: Power Off
 t2: Power on/off test 10 times (on 2 min / off 5min)
 t3, t4: Run burn in test 7.0
 t5: Win 7 Software restart test 3 times
 Test Software: Windows 7

Test Result:

- a. No issues were found during the cold start test.
- b. No issues were found during the hot start test.